

**Search Notes**

Application/Control No.

10/823,469

Examiner

Lan Nguyen

Applicant(s)/Patent under  
Reexamination

NAIK ET AL.

Art Unit

3683

**SEARCHED**

Class	Subclass	Date	Examiner
303	122.07	9/23/05	XLN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
TEXT search included	9/23/05	XLN